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RELY,
A PROGRAM FOR ESTIMATING
OVERALL SYSTEM RELIABILITY BASED ON
COMPONENT, SYSTEM AND
FLIGHT DATA

THOMAS A. NEEF

MARCH 1969

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PICATINNY ARSENAL
DOVER, NEW JERSEY



TECHNICAL MEMORANDUM 1891

RELY,

A PROGRAM FOR ESTIMATING
OVERALL SYSTEM RELIABILITY BASED ON
COMPONENT, SYSTEM AND
FLIGHT DATA

BY

THOMAS A. NEEF

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DATA PROCESSING SYSTEMS OFFICE
PICATINNY ARSENAL
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ABSTRACT

This report documents a program for estimating overall system reliability by judiciously combining individual component data, laboratory test data and finally flight data as gathered at two different periods in time. All data used in arriving at this single reliability estimate is assumed to be attribute in nature.

INTRODUCTION

In July 1968, the Munitions Command requested the Mathematical Analysis Division of the Data Processing Systems Office to develop a computer program (using their prescribed methodology) to estimate overall system reliability. Such a program has been created, herein called RELY, which requires as input six sets of distinct attribute type data which should commonly arise during the development phase of a missile assembly or subassembly program. The six sets of basic inputs consist of the three types of data listed below gathered at two distinct time periods:

- (1) Component data as naturally arising from individual component tests.
- (2) Laboratory systems data arising from testing a component assembly (i.e. circuit) in a laboratory and
- (3) Flight data consisting of data resulting from actual test firings containing all circuitry.

The program judiciously combines this data so as to produce a single estimate for overall system reliability.

This report describes in detail this computer program and includes a complete description of input-output formats, a discussion of the program logic and a sample case. It should be emphasized however, that this report does not describe the foundations of the methodology utilized. For this the interested reader is referred to Reference 1.

GENERAL PROGRAM OUTLINE

To simplify the discussion the following mathematical notation has been adopted.

Mathematical Notation:

A_{ij} $A = N$ refers to number of tests conducted at i th stage at time T_j

(basic inputs) $A = C$ refers to number of successes resulting from testing at the i th stage at time T_j

Subscript definition:

$i = c$ (Component stage) refers to component data .

$i = s$ (System stage) refers to system data, i.e.

resulting from testing circuits comprised of the above components

$i = f$ (flight stage) refers to flight data, i.e.

resulting from flight tests containing the circuitry above

$j = 0$ refers to time T_0

$j = 1$ refers to time T_1 where $T_0 < T_1$

Thus N_{s1} refers to the number of systems tests conducted at time T_1 ,

while C_{f0} refers to the number of flight successes obtained at time T_0 .

K_i refers to a weighting factor that weights the less significant T_0 data when combining with T_1 data. i again refers to component ($i=c$), systems ($i=s$) or flight ($i=f$) data.

A_{ieq} refers to the equivalent number of tests ($A=N$), or equivalent number of successes ($A=C$) for either component, system or flight data, ($i=c, s, f$ respectively). These values arise by appropriate combination of N_{co} , C_{co} , N_{c1} , C_{c1} , K_c to obtain N_{ceq} and C_{ceq} , or more generally by combination of A_{i0} , A_{i1} and K_i , to produce A_{ieq} .

K_{ieq} refers to the weight given to the equivalent component data, when combining with the equivalent system data ($i=s$), to produce combined component-system data. When $i=f$, this variable refers to the combination of the component-system data with the equivalent flight data to produce the overall equivalent number of tests N_{eq} and overall equivalent number of successes C_{eq} used to arrive at P_{best} .

P_{best} refers to the overall system reliability = C_{eq}/N_{eq}

The interrelationships existing between the various data sets are exhibited in Figure 1. Figure 2 is a schematic diagram showing the relative significance of the involved data sets.

The underlying approach to arrive at P_{best} , the single estimate

of overall reliability, is to combine all like data sets, degrading however, the less significant T_0 data, when combining with the more significant T_1 data. Similar degradation factors apply when combining the less significant equivalent component data, with the more significant equivalent system data and the more significant, yet, flight data.

Each such combination of data will be described, thus yielding in the process a general program outline.

I. Combination of component data N_{co} , C_{co} , N_{c1} , C_{c1} to produce N_{ceq} , C_{ceq} .

A. One component case.

Here N_{co} , C_{co} , N_{c1} , C_{c1} embody the inputs to this calculation. The values for the above are obtained from actual testing, witnessing for example C_{co} success out of N_{co} tests at time T_0 .

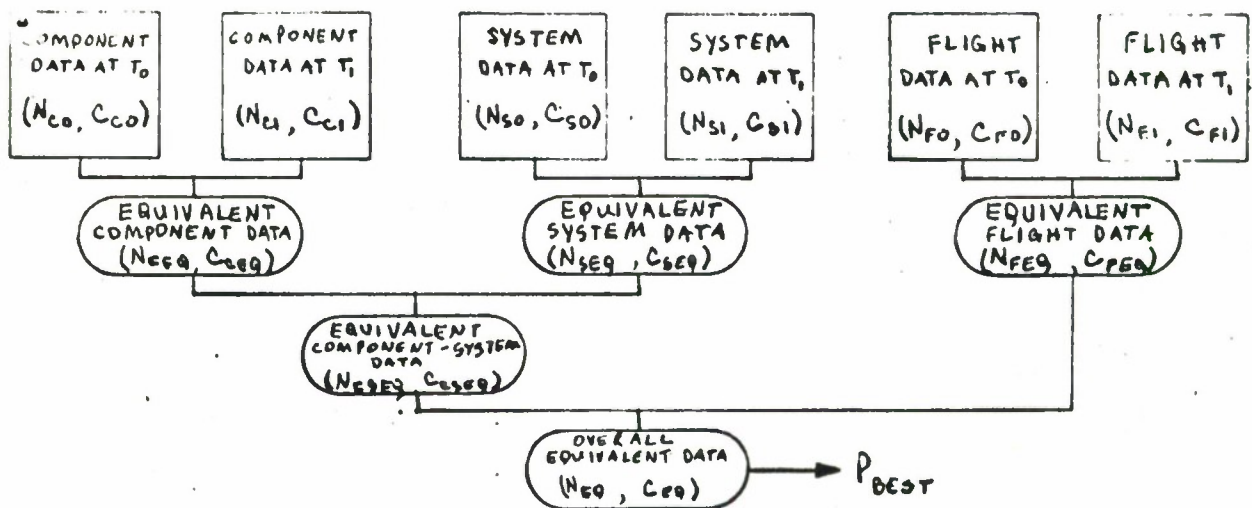
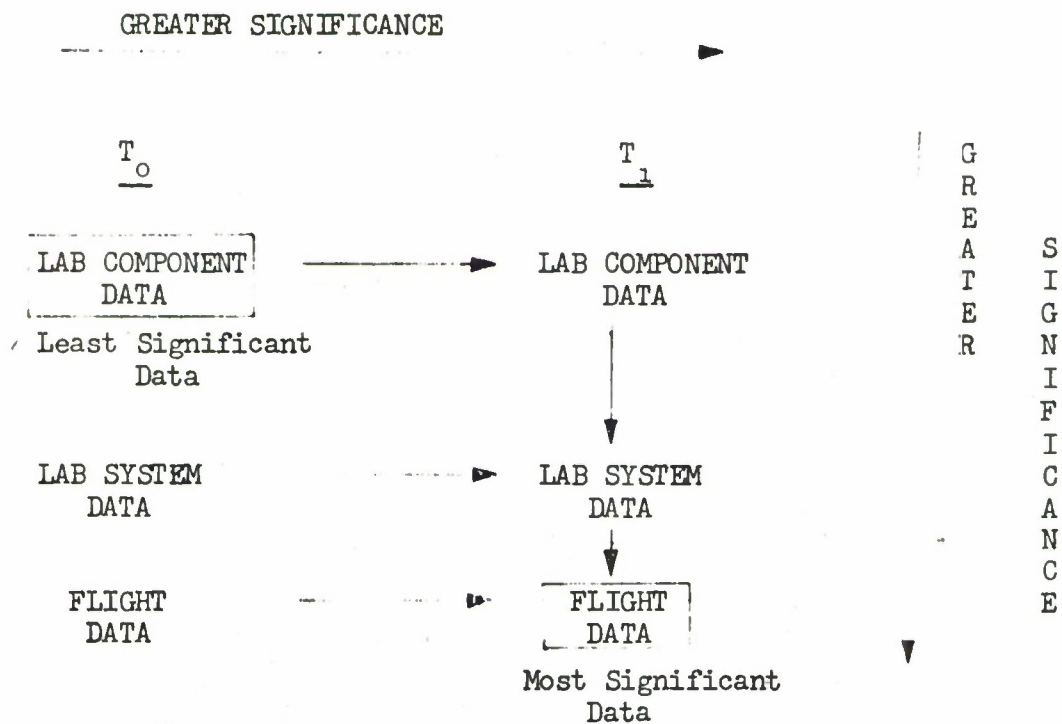


FIGURE 1



RELATIVE SIGNIFICANCE OF DATA

FIGURE 2

It is assumed that P , the true probability of component functioning is β -distributed with N_{co} , C_{co} as parameters, i.e.

$$\beta_o(P) = \frac{\Gamma(N_{co} + 2)}{\Gamma(C_{co} + 1) \Gamma(N_{co} - C_{co} + 1)} P^{C_{co}} (1-P)^{N_{co}-C_{co}} \quad (1)$$

with a similar expression $\beta_1(P)$ for components tested at time T_1 . The T_0 data is degraded by the area, K_c , common to the two β -distributions, as expressed in the following equations that yield the equivalent component data.

$$N_{ceq} = N_{co} \cdot K_c + N_{c1}; \quad C_{ceq} = C_{co} \cdot K_c + C_{c1} \quad (2)$$

K_c is interpreted geometrically in the Diagram below

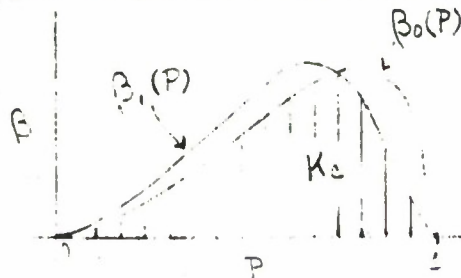


DIAGRAM 1

Thus if $N_{co} = N_{c1}$ and $C_{co} = C_{c1}$ the two distributions would coincide and the degradation factor would be 1 (i.e. no degradation).

B. Several Component case.

When several different component types are involved and related by a specific circuit equation, calculations additional to those above are necessary. In this case it is required to compute a N_{ceq} and C_{ceq} for each component type and combine the results. Let $N_{ceq}(k)$ and

$C_{ceq}(k)$ represent the above values referred to the k-th component type.

An equation similar to equation (1) is constructed with these values

i.e.

$$\beta(P, k) = \frac{\Gamma(N_{ceq}(k) + 2)}{\Gamma(C_{ceq}(k) + 1) \Gamma(N_{ceq}(k) - C_{ceq}(k) + 1)} Q \quad (3)$$

where

$$Q = P^{C_{ceq}(k)} (1 - P)^{N_{ceq}(k) - C_{ceq}(k)}$$

This represents the probability density P of the k-th component type in the light of both T_0 and T_1 data. The calculation to combine each $N_{ceq}(k)$ and $C_{ceq}(k)$ to produce N_{ceq} and C_{ceq} then proceeds in a Monte Carlo fashion involving the circuit.

Values are sampled from each of the β -distributions* and inserted into the specified circuit equation, from which the probability of circuit functioning, R_s for these values, is obtained. It is important to note that if a given component type appears several times in the circuit, the corresponding β -distribution is sampled only once per simulation. Performing this simulation M times thus yields M values for the probability of circuit functioning. The assumption is made that these M values are β -distributed. Consequently the mean μ , and the variance σ^2 of these numbers are computed and set equal to the mean and variance of the β -distribution.

*This is accomplished by numerically determining the cumulative distribution and finding the P corresponding to $RN = \int_0^1 \beta(k, X) dX$ where RN is a random number between 0 and 1. The integral is tabulated as a function of P , so that for given RN , linear interpolation applies for ascertaining P .

This allows for the two unknown parameters in this distribution to be solved. These unknowns correspond in fact to the N_{ceq} and C_{ceq} of Figure 1. Mathematically, this procedure is equivalent to the equations that follow.

$$\mu = \frac{\sum_{i=1}^M R_s(i)}{M} \quad \sigma^2 = \frac{\sum_{i=1}^M R_s^2(i) - 2\mu \sum_{i=1}^M R_s(i) + M\mu^2}{M} \quad (4)$$

$$N_{ceq} = \frac{\mu(1-\mu) - 3}{\sigma^2} \quad C_{ceq} = \frac{\mu^2(1-\mu) - (1+\mu)}{\sigma^2} \quad (5)$$

II. Combination of system data N_{so} , C_{so} , N_{s1} , C_{s1} to produce N_{seq} and C_{seq} ,

This combination is accomplished analogously to equations (1) where the degradation factor is again the area common to the two distributions. Thus

$$\beta_o(P) = \frac{\Gamma(N_{so} + 2)}{\Gamma(C_{so} + 1) \Gamma(N_{so} - C_{so} + 1)} P^{C_{so}(1-P)} N_{so}^{N_{so}-C_{so}}$$

$$\beta_1(P) = \frac{\Gamma(N_{s1} + 2)}{\Gamma(C_{s1} + 1) \Gamma(N_{s1} - C_{s1} + 1)} P^{C_{s1}(1-P)} N_{s1}^{N_{s1}-C_{s1}}$$

$$K_s = \int_0^1 \text{Min}\{\beta_o(P), \beta_1(P)\} dP \quad (6)$$

$$N_{seq} = N_{so} \cdot K_s + N_{s1}$$

$$C_{seq} = C_{so} \cdot K_s + C_{s1}$$

III. Combination of flight data N_{fo} , C_{fo} , N_{f1} , C_{f1} to produce N_{feq} , C_{feq} .

This again is completely analogous to II with N_{so} , ..., C_{s1} replaced by N_{fo} , ..., C_{f1} respectively.

IV. Combination of equivalent data produced in I, II, and III to produce N_{eq} , C_{eq} .

The combination of N_{ceq} , C_{ceq} with N_{seq} , C_{seq} to produce $N_{c,seq}$, $C_{c,seq}$ and the combination of these last two values with N_{feq} , C_{feq} to produce N_{eq} , C_{eq} are also completely analogous to II with the A_{ceq} replacing the A_{so} and the A_{seq} replacing the A_{s1} in the first case and the $A_{c,seq}$ replacing the A_{so} and the A_{feq} replacing the A_{s1} in the second case. Thus the last equation in (6) becomes $C_{c,seq} = C_{ceq}$. $K_{seq} + C_{seq}$ when combining components and system data, and becomes $C_{eq} = C_{c,seq}$. $K_{feq} + C_{feq}$ when combining component-systems data with flight data.

V. Calculation of overall system reliability, P_{best} .

$$P_{best} = \frac{C_{eq}}{N_{eq}} \quad (7)$$

For output purposes, the following two variable are also computed by the equations that follow

$$\begin{aligned} \mu &= \frac{C_{eq} + 1}{N_{eq} + 2} \\ \text{VARIANCE} &= \frac{(C_{eq} + 1)(N_{eq} - C_{eq} + 1)}{(N_{eq} + 2)^2 (N_{eq} + 3)} \end{aligned} \quad (8)$$

COMPUTER PROGRAM DESCRIPTION

A. Description of MAIN program

This Section describes the computer program that evaluates the mathematical model. It is believed that sufficient information is contained herein along with COMMENT statements in the program listing to enable one to understand and possibly modify the program. Figure 3 is an overall flow chart giving the sequence of the computations. Not shown in the figure is the fact that much of the routine calculations such as the tabulation of the β -distribution, numerical integration etc. are relegated to subroutines. These subroutines though briefly referred to in the text are more fully described at the end of this Section.

All inputs are read in the MAIN program, thereupon one set of component data is selected, being the values for N and C at time T_0 and values for N and C at T_1 . Using these four values (labelled in the program as NCO, CCO, NCL, CCL respectively) as input arguments the value $KA (=K_c$ of Diagram 1) is ascertained from a subprogram K. The T_0 data is then degraded by this factor and the result added to the T_1 data to yield two new intermediate values, SUB1, corresponding to the number of trials and SUB2 corresponding to the number of successes as in equation (2) (page 7). Using these intermediate values as parameters a β -distribution (corresponding to equation 3) is constructed and tabulated in subroutine BETAF. The tabulation is effected at equally spaced abscissas depending upon the value of DELTAP which should lie

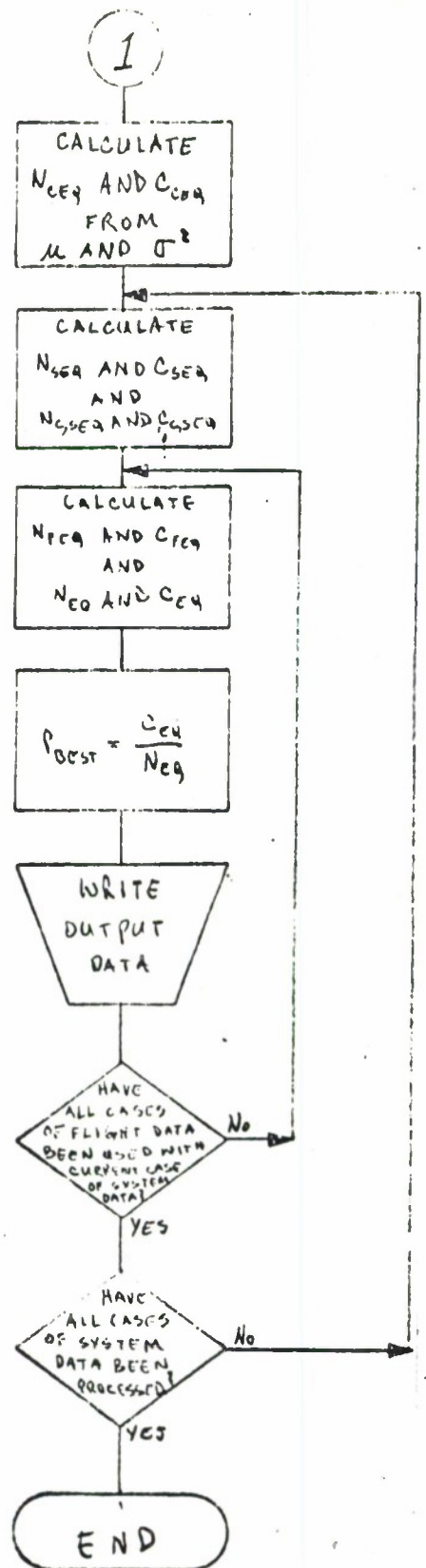
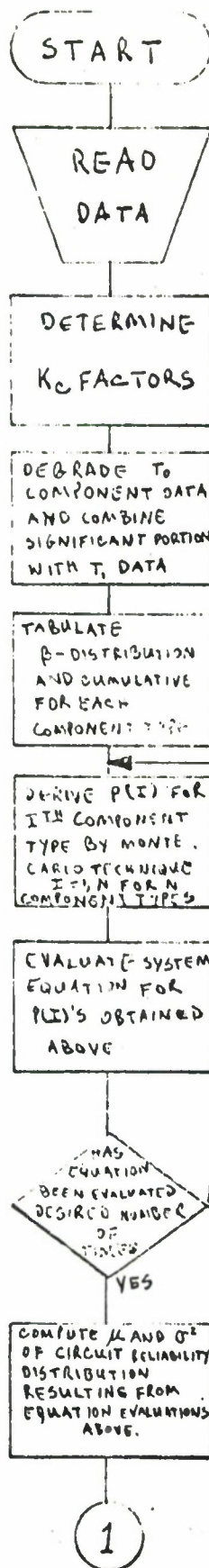


Figure 3

in the interval $[.01, .5]$. It is from this density function that the probability of component functioning is sampled and subsequently inserted into the circuit equation. To accomplish this, the cumulative of this distribution is tabulated and placed in an array A(I) (subroutine DQSF), a random number, (RDM(1)), selected and the corresponding P value determined by linear interpolation in subprogram INTERP. This calculation is repeated for each component type, and all results are ultimately substituted into the circuit equation from which a probability of circuit functioning, (RS), is computed. At this point a running count of these RS values for output purposes in histogram form is maintained, along with running summations of the RS values and RS^2 values for use in calculating the mean μ and variance σ^2 of these generated numbers (equations 4). At the end of the simulation loop, equations (5) are used to produce N_{ceq} and C_{ceq} which are labelled as NCEQ and CCEQ in the program. Remaining calculations involving system and flight data, and all combinations thereof are analogous to what has been described and again typically involve use of the BETAF and K routines. The notation, too, in remaining segments of the MAIN program is quite suggestive so that the reader will find for example N_{so} , C_{seq} , and P_{best} are represented in the program as NSO, CSEQ and PBEST.

B. Description of Subprograms (in alphabetical order)

1. FUNCTION AREAF (B,J)

Common DELTAP

Description of arguments:

B - one-dimensional equidistantly tabulated function the area under which is to be computed.

J - the number of values in B.

DELTAP - interval width

Operation:

Calculates the area under B by Simpson's rule, (therefore J must be odd). The output is a scalar representing the area under the curve.

2. SUBROUTINE BETAF (N, C, BETA, J, PB)

Common DELTAP

Description of arguments:

Input Arguments:

N,C - input parameters for the beta-distribution equation

Output Arguments:

BETA - one dimensional beta-distribution array produced in the subroutine

J - number of values in array (dependent upon DELTAP)

PB - one dimensional array of P-values used in generating the beta distribution

DELTAP - interval width

Operation:

Produces an equidistantly tabulated beta-distribution

using the following equation:

$$\beta = G P^C (1 - P)^{N - C} \quad (9)$$

where G is a constant,

$$G = \frac{\Gamma(N + 2)}{\Gamma(C + 1) \Gamma(N - C + 1)} = \frac{(N+1)!}{C!(N-C)!} \quad (10)$$

and is computed in subroutine GAMA, P varies from 0.0 to 1.0 in increments of DELTAP

In order to avoid problems arising from zero bases and/or zero exponents in the exponentiation routine, the equation is evaluated for one of four cases as:

1. N and C are distinct and nonzero.
2. N and C are identical and nonzero.
3. N is nonzero but C is zero.
4. Both N and C are zero.

3. SUBROUTINE DQSF (H, Y, Z, NDIM)

This subprogram is part of the IBM System/360 SCIENTIFIC SUBROUTINE PACKAGE and a detailed description of its arguments and operation can be found therein. Briefly, however, this subroutine performs the integration of an equidistantly tabulated function by Simpson's Rule. It computes a vector of integral values Z_i for a table of functional values

Y_i , $i = 1, 2, \dots, N$ given at equidistant points $X_i = a + (i-1)h$

$$Z_i = Z(X_i) = \int_a^{X_i} Y(X) dx \quad (i = 1, 2, 3, \dots, N)$$

4. FUNCTION GAMA (ARG1, ARG2, ARG3)

Description of arguments:

ARG1 - corresponds to N+2 in equation (10) of subroutine
BETAF

ARG2 - corresponds to C+1 in equation (10) of subroutine
BETAF

ARG3 - corresponds to N-C+1 in equation (10) of subroutine
BETAF

Operation:

The IBM - supplied subroutine GAMMA evaluates the GAMMA function for a given argument provided the argument is less than or equal to 57. The subroutine GAMA is designed to reduce each of the arguments ARG1, ARG2, ARG3, to 57, if necessary, before calling GAMMA for each of them.

Furthermore it computes G

$$G = \frac{\Gamma(\text{ARG1})}{\Gamma(\text{ARG2}) \Gamma(\text{ARG3})} \quad (11)$$

for use in subroutine BETAF. Output is scalar value for G.

5. SUBROUTINE GAMMA (XX, GX, IER)

This subroutine is part of the SCIENTIFIC SUBROUTINE PACKAGE except that was changed to double precision for this program. Briefly the operation of this subroutine is to evaluate the gamma function for a given value of XX, where $\Gamma(X)$ is defined for $X > 0$ by

$$\Gamma(X) = \int_0^\infty t^{X-1} e^{-t} dt$$

which satisfies the recurrence relation $\Gamma(X) = (X-1)\Gamma(X-1)$

which defines $\Gamma(X)$ for any X non-negative integer i.e.

$$\Gamma(X) = (X-1)!$$

6. FUNCTION INTERP (I, J, F, YFL)

Common /BLKL/AX

Description of arguments:

I - component type designation

J - number of values in ITH row of two-dimensional array
AX corresponding to array AREA of the MAIN program, in
which the scalar input YFL will be interpolated.

F - the one-dimensional array from whose elements the
interpolated value is to be calculated.

YFL - number whose corresponding value is to be found by
interpolation

AX - subroutine name for array AREA of MAIN program which
stores cumulative for each component type.

Operation:

Straight-forward linear interpolation is effected herein.

7. FUNCTION K (NO, CO, NI, CI)

Common DELTAP

Description of arguments

NO, CO - number of trials and number of successes at time
 T_0 (or analogous parameters)

Nl, Cl - number of trials and number of successes at most
recent testing T_1 (or analogous parameters)

DELTAP - interval width

Operation:

K is designed to produce a proportionality factor for degrading the less significant data, NO, CO (before it is combined with the more significant data Nl, Cl in MAIN program). This is accomplished by first tabulating the beta-distributions for NO, CO and for Nl, Cl by calling subroutine BETAF. The area under the intersection of these two curves, CMAREA, is found next by comparing the two beta curves point-for-point, in each case taking the smaller of the two values (ordinates), putting it into a new array, and computing the area under this curve in subroutine AREAF. AREAF is also used to find the area, TIAREA, under the beta curve for the most significant data Nl, Cl (this area should be close to or exactly equal to 1.0 and is computed and used as a self adjusting calculation to account for digital round-off error). K is then set equal to CMAREA divided by TIAREA. The output of this subroutine is the scalar significance factor, K.

PROGRAM OPERATION

This Section describes the inputs necessary to run the program RELY as well as a description of the output variables. To allow for the desirability of analyzing several different system and/or flight data sets for a given set of component data, the inputs have been so arranged to facilitate these additions with a minimum of card entries. One may note, further, that since the bulk of the calculations are concerned with component data, additional results depending on varying system or flight data sets require only a small investment of computer running time for the added evaluation.

To operate the program RELY the probability equation for the circuit must be inserted into the program between the COMMENT statements MATH MODEL-BEGIN and MATH MODEL-END (see program listing). In doing this one should number each component type in any convenient manner so that a correspondence exists between the component test results and the same component in the circuit. An example for a simple circuit is contained in the sample inputs. In addition values for the variables listed below must be supplied in the format indicated, as well as the actual component, system and flight input data.

| <u>VARIABLE</u> | <u>DESCRIPTION</u> | <u>FORMAT</u> |
|-----------------|--|---------------|
| T | Time between testing dates (months). | I2 |
| NRS | Number of times the circuit equation is to be evaluated (NRS>1) i.e. number of Monte Carlo simulations, limited only by format size and computer running time. | I6 |

| <u>VARIABLE</u> | <u>DESCRIPTION</u> | <u>FORMAT</u> |
|-----------------|--|---------------|
| DELTAP | (ΔP) Desired increment on P-values in setting up Beta-distributions and reliability distribution ($.01 \leq \Delta P \leq .5$) | F6.4 |
| NCOMP | Number of distinct component types in the circuit ($1 \leq NCOMP \leq 100$) | I4 |
| NSYDT | Number of system data sets to be used with a given set of component data ($1 \leq NSYDT \leq 100$) | I4 |
| NFLDT | Number of flight data sets to be used in conjunction with the given component data set ($1 \leq NFLDT \leq 100$) | I4 |

Values for these six variables form the first card of the data deck. This card is followed by: the component data set, which contains one card for each component type, the laboratory system data set and finally the flight data set. Each card of each set has the same format (4I6). The four values on these cards are N_{i0} , C_{i0} , N_{i1} , C_{i1} in that order. The first card of the component data set must contain the data corresponding to the first component as labelled in the circuit equation, the second card contains data for component 2, and so forth for all component data.

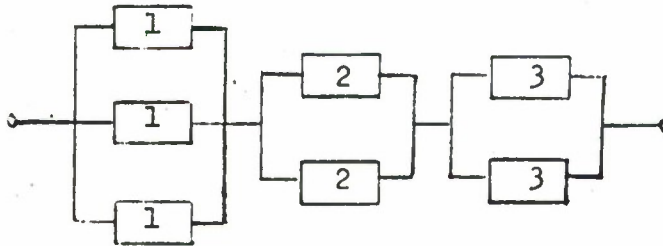
All data cards of the system and flight data sets are set up exactly like those of the component data set, the order of cards within each set being entirely arbitrary. All combinations of system and flight data, will be evaluated when $NSYDT > 1$ and $NFLDT > 1$, all cases of flight data being combined in turn with each case of system data. The program may be run without system and/or flight data. In this case $NSYDT$ and/or $NFLDT$ must be set equal to 1, and the appropriate data set must

consist of one blank card.

For a description of the output of program RELY, refer to the sample case, page 25.

SAMPLE CASE

As a sample case consider the simple circuit configuration below. It consists of seven components but only three distinct component types: type 1, type 2, type 3.



The probability equation for this circuit is

$$R_s = (1 - (1 - P(1))^3) (1 - (1 - P(2))^2) (1 - (1 - P(3))^2)$$

where $P(i)$ is the probability of component type i functioning properly.

Typical input data for this circuit is presented in the table on the next page. It will be noted, for example, that components of type 2 worked satisfactorily 42 times out of 44 trials during the first round of testing (T_0) but twenty four months later (T_1), worked only 38 times in 44 trials.

In order to compute an estimate of overall system reliability for this circuit based on the data compiled in the following table using program RELY it is necessary to:

1. Insert the circuit equation into the program between the comment cards MATH MODEL - BEGIN and MATH MODEL - END (See Listing which contains this example).

| | FIRST ROUND OF TESTING (TIME T_0) | | SECOND ROUND OF TESTING (TIME T_1) | |
|--|---|--------------------------------|--|--------------------------------|
| | <u>Number of trials</u> | <u>Number of successes</u> | <u>Number of trials</u> | <u>Number of successes</u> |
| COMPONENTS: | | | | |
| TYPE 1 | 66 | 57 | 66 | 54 |
| TYPE 2 | 44 | 42 | 44 | 38 |
| TYPE 3 | 44 | 40 | 44 | 35 |
| LABORATORY SYSTEM DATA: | | | | |
| FIRST CASE | 22 | 22 | 22 | 22 |
| SECOND CASE | 22 | 22 | 22 | 18 |
| FIELD SYSTEM DATA (only one case was used for this particular run) | 4 | 4 | 4 | 3 |

Input Data
for
Sample Case

2. Set up a data deck consisting of (refer to fig. 4):

a. One card containing 6 input parameters.

| | <u>Columns</u> | <u>Value</u> | |
|--------|----------------|--------------|---|
| T | 1-2 | 24 | It is assumed twenty four months elapsed between the two rounds of testing. (T used only for printout). |
| NRS | 3-8 | 10000 | Number of simulations. Here the circuit equation will be evaluated 10,000 times in determining N_{ceq} , C_{ceq} . |
| DELTAP | 9-14 | .01 | ΔP - Increment on P This will cause the Beta-distributions and reliability histogram to be formed in steps of .01 along the horizontal-axis, P. |
| NCOMP | 15-18 | 3 | Number of distinct component types. There are three distinct types of components in this circuit even though there is a total of seven components. |
| NSYDT | 19-22 | 2 | Number of cards in the system data set. Since there are two cases of laboratory system data, there must be two data cards in the system data set, as governed by this 2. |
| NFLDT | 23-26 | 1 | Number of cards in flight data set. For this particular run there is only one case of flight data and consequently there is only card in the flight data set. |

FLIGHT
DATA
SETSYSTEM
DATA
SET

COMPONENT
DATA
SET

INPUT PARAMETERS

DATA DECK FOR SAMPLE CASE

FIGURE 4

b. Component Data Set - consists of three data cards, one for each of the three distinct component types in the sample circuit. Card 1 contains the data for the component type labeled #1 in the circuit diagram and circuit equation; card 2 contains the data for component type 2; and card 3 contains data for component type 3. This correspondence between component numbering in the circuit diagram and circuit equation and the ordering of cards in the data deck is essential, however the initial assignment of numbers to the different component types in the circuit is completely arbitrary. Each card in this data set contains the appropriate four values taken from the table of test results above. For example, card 1 contains the number of trials 66 and corresponding number of successes, 57, for component 1 from the first round of testing at time T_0 , followed by the test results from round two, time T_1 : 66, 54. The numbers are typed in the first 24 columns (6 columns per number, right-adjusted format-4I6).

c. System Data Set - consists of two data cards: one for each of the two cases of laboratory system tests. For example, the first card in this set contains the results of the first case compiled during the first round of tests, time T_0 - 22 trials, 22 successes, followed by those of the second round of tests, time T_1 - 22 trials, 22 successes. The format of the cards in this set is identical to that of the cards in the component data set.

d. Flight Data Set - this data is set up exactly like the previous two sets except that the data are the results of testing the

system in the field.

The output of program RELY as exhibited in the output listing of the sample case, Figure 5, consists of a listing of the input values in tabular form which shows the order in which the system and flight data are evaluated. The system reliability histogram showing the distribution of the R_s values calculated from the circuit equation is exhibited next. The mean and variance are also printed from which N_{ceq} and C_{ceq} are computed. Finally the calculated values for all the A_{ieq} and intermediate variables as well P_{best} , μ and Variance for all cases of system and flight data combinations are listed. The printout of the histogram begins with the line preceeding the first appearance of a non-zero element in the distribution. For example, in the output of the sample case, the smallest R_s value computed in the 10,000 simulations fell in the range $.77 < R_s \leq .78$, so the first line printed was for $P = .77$.

LAB COMPONENT INPUT DATA

$$1 = T1 - 10 = 24$$

| COMPONENT | TO | | T1 | |
|-----------|----|----|----|----|
| | N | C | N | C |
| 1 | 66 | 57 | 66 | 54 |
| 2 | 44 | 42 | 44 | 38 |
| 3 | 44 | 40 | 44 | 35 |

SYSTEM AND FLIGHT INPUT DATA

| CASE # | TO | | T1 | |
|--------|-------------|-------------|-------------|-------------|
| | SYSTEM N | FLIGHT C | SYSTEM N | FLIGHT C |
| 1 | 22 | 4 | 22 | 4 |
| 2 | 22 | 4 | 22 | 4 |

RELIABILITY HISTOGRAM FOR EQUIVALENT-SYSTEM FOR COMPONENTS

| P |
|-------|
| C.77C |
| 0.78C |
| C.79C |
| 0.80C |
| C.81C |
| 0.82C |
| C.83C |
| 0.84C |
| C.85C |
| 0.86C |
| C.87C |
| 0.88C |
| C.89C |
| 0.90C |
| C.91C |
| 0.92C |
| C.93C |
| 0.94C |
| C.95C |
| 0.96C |
| C.97C |
| 0.98C |
| C.99C |
| 1.00C |

DISTRIBUTION

| |
|------|
| 0 |
| 1 |
| 0 |
| 0 |
| 2 |
| 1 |
| 4 |
| 3 |
| 18 |
| 34 |
| 37 |
| 90 |
| 158 |
| 283 |
| 488 |
| 760 |
| 1132 |
| 1511 |
| 1774 |
| 1820 |
| 1318 |
| 498 |
| 67 |
| 1 |

MEAN = 0.93930 D 0C
VARIANCE = C.54983 D-03

FIGURE 5

NUMBER OF SIMULATIONS = 10000

CASE # 1 NCEQ = 100.68544 CCEQ = 95.45660 ASEQ = 44.00000 CSEC = 44.00000 ACSEQ = 76 82919 CCSEQ = 75.12305
NFEQ = 6.36160 CFEQ = 5.36160 NEQ = 17.40282 CEC = 16.15763
PBEST = 0.92E45 MU = 0.8E429 VARIANCE = 0.00502

CASE # 2 NCEQ = 100.68544 CCEQ = 95.45660 ASEQ = 25.53925 CSEC = 21.53925 ACSEQ = 43 85685 CCSEQ = 38.90488
NFEQ = 6.36160 CFEQ = 5.36160 NEQ = 28.87628 CEC = 25.33410
PBEST = 0.87733 MU = 0.85289 VARIANCE = 0.00394

REFERENCE

1. Naval Ammunition Depot, Oahu, Hawaii, 21 January 1969, "A Proposed Tri-Service Approach for Reliability Assessment", Appendix D.

APPENDIX I

CARC
NUMBER[illegible]

```

59      INF1(J),CF1(J)
60      DO 104 I=1,NCCMF
61          NC = NC0(I)
62          CC = CC0(I)
63          N1 = N1(I)
64          C1 = C1(I)
65          KA = K(INC,CC,N1,C1)
66          SU91 = NC*KA + N1
67          SU12 = CC*KA + C1
68
69      C SETLP COMPONENT RELIABILITY HISTOGRAM FOR ITH COMPONENT
70      C
71      CALL GETAF(SU91,SU92,BETA,J,PR)
72
73      C CALL SUBROUTINE TO PRODUCE CUMULATIVE FOR ITH COMPONENT
74      C
75      CALL DCSFIDELTAP,BETA,A,J)
76
77      C PUT THE VECTOR, A, OF INTEGRAL VALUES PRODUCED IN THE SUBROUTINE FOR THE ITH
78      C COMPONENT INTO THE ITH ROW OF THE AREA ARRAY.
79      C
80      DO 104 N=1,J
81          104 AREAT(N) = A(N)
82
83      C INITIALIZE STORAGE AREAS AND VARIABLE LOCATIONS.
84      C
85      DO 105 M = 1,J
86          105 DISTIM = 0
87          SM2S = 0.0
88          SMRSSC = 0.0
89          NCF0 = 0.0
90          CCF0 = 0.0
91          RSMEAN = 0.0
92          VAR = 0.0
93          IJ = J
94
95      C BEGIN MOUNT CARLC PROCESS WITH WHICH TO DEVELOP THE EQUIVALENT-SYSTEM
96      C RELIABILITY DISTRIBUTION FOR COMPONENTS
97      C
98      DO 111 L=1,NBS
99          RS = 0.0
100         DO 107 I=1,NCCMF
101             YEL = RDM(I)*AREAT(I,J)
102
103         C THE RANDOM NUMBER SELECTED FOR THE ITH COMPONENT IS MULTIPLIED BY THE
104         C LARGEST VALUE IN THE APPROPRIATE CUMULATIVE AS A SELF-ADJUSTING
105         C CALCULATION TO ACCOUNT FOR DIGITAL ROUNDOFF ERROR
106
107         107 P(I) = INTERP(I,J,PR,YEL)
108
109         C *****
110         C MATH MODEL - BEGIN
111         RS = (1.0-(1.0-P(I))**3)*(1.0-(1.0-P(2))**2)*(1.0-(1.0-P(3))**2)
112         C MATH MODEL - END
113
114         C *****
115
116

```

CARC
NUMBER

```

117 SMRS = SMRS + RS
118 SMRSSC = SMRSSC + RS**2
119 SAVE = L
120
121 C SET UP RELIABILITY DISTRIBUTION, DIST(M)
122 C
123 M = J + 1
124 M = M - 1
125 IF (1.0 - RS .LT. DELTA) GO TO 108
126 IF (PR(M) - RS) 13, 14, 12
127 14 IF (QS .GT. C.C .CR. RS .EG. 1.0) GO TO 108
128 13 M = M + 1
129 108 DIST(M) = DIST(M) + 1
130 IF (M .LT. IJ) (J=M
131 111 CONTINUE
132 IJ=IJ+1
133 WRITE (4,250)
134 WRITE (6,203) ((PR(IJ), DIST(IJ)), JJ=1,J)
135 RMSEAN = SMRS/SAVE
136 VAR = (SMRSSC - 2.0*RS*FAN*SMRS + RMSEAN**2*SAVE)/SAVE
137 WRITE (6,210) RMSEAN, VAR
138 WRITE (4,250)
139 WRITE (6,214) ARS
140 IF (VAR) 51, 51, 16
141 15 X = RMSEAN
142
143 C COMPUTE A-EQUIVALENT AND C-EQUIVALENT FOR COMPONENTS
144 C
145 CCEQ = (X**2*(1.0 - X))/VAR - (1.0 + X)
146 MCEQ = X*(1.0 - X)/VAR - 3.0
147 NCASF = 0
148
149 C DEVELOP EQUIVALENT SYSTEM FOR LAF SYSTEM DATA AND COMBINE IT WITH
150 C EQUIVALENT SYSTEM FOR LAB COMPONENT DATA, YIELDING C,S EQUIVALENT SYSTEM
151 C
152 DO 112 I=1, NSYNT
153 MC = NSO(I)
154 CC = CSO(I)
155 N1 = NSI(I)
156 C1 = CSI(I)
157 NSEQ=C.O
158 CSEQ=C.O
159 MCSFO=C.O
160 CCSFO=C.O
161 IF (NC .EQ. 0.0 .AND. N1 .EQ. 0.0) GO TO 114
162 KA = X*(NC, C1, N1, C1)
163 NSEQ = N1 + NO*KB
164 CSEQ = C1 + CC*KB
165 114 KC = X*(NCEQ, CCEQ, NSEQ, CSEQ)
166 KSE = 1.0
167 KSEPRM = 1.0
168 MCSEQ = KSF*NSEQ + KSEPRM*MC*NCEC
169 CCSEQ = KSE*CSEQ + KSEPRM*CC*CEC
170
171 C DEVELOP EQUIVALENT SYSTEM FOR FLIGHT DATA AND COMBINE IT WITH C,S
172 C EQUIVALENT SYSTEM, YIELDING FINAL EQUIVALENT SYSTEM REFLECTING ALL SIGNIFICANT
173 C DATA FROM WHICH THE BEST ESTIMATE OF SYSTEM RELIABILITY, PREST, IS COMPUTED
174 C

```

CARD
NUMBER

```

175 20 113 V=1,NEQ1
176 NC = N*(M)
177 CC = C*(M)
178 N1=N*(M)
179 C1=C*(M)
180 NFEQ=C*2
181 CFEQ=C*2
182 NFEQ=C*2
183 CFEQ=C*2
184 NFEQ=C*2
185 CFEQ=C*2
186 NFEQ=C*2
187 CFEQ=C*2
188 NFEQ=C*2
189 CFEQ=C*2
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225 CFEQ=C*2
226 NFEQ=C*2
227 CFEQ=C*2
228 NFEQ=C*2
229 CFEQ=C*2
230 NFEQ=C*2
231 CFEQ=C*2
232 NFEQ=C*2
233 CFEQ=C*2

```

113 CONTINUE

50 WRITE (4,207)

51 WRITE (5,208)

52 CALL F41

END

FUNCTION AREAF(P,J)

PURPOSE

TO CALCULATE THE AREA UNDER A CURVE BY SIMPSON'S RULE.

DESCRIPTION OF ARGUMENTS

A - CASE-DEPENDENT EQUIDISTANTLY TABULATED FUNCTION THE AREA UNDER WHICH IS TO BE COMPUTED.

J - THE NUMBER OF VALUES IN A.

DOUBLE PRECISION FUNCTION AREAF(P,J)

DOUBLE PRECISION A(101), DELTAP, CFC,EVEN

COMMON DELTAP

DO = 1.0

EVEN = 1.0

L = J-1

GO TO 100 (2,1,2)

EVEN = EVEN + 1

DO = 1.0 + A(I+1)

AREAF = (DELTAP/3.0)*(P(1) + 4.0*(EVEN + 1) + 2.0*(P(L+1) + P(L)))

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SUBROUTINE BETAF(N,C,BETA,J,PR)
 PURPOSE
 TO PRODUCE AN EIGHTEENTH TABULATED BETA-DISTRIBUTION
 DESCRIPTION OF ARGUMENTS
 N,C - INPUT PARAMETERS FOR THE BETA-DISTRIBUTION
 FUNCTION.
 BETA - ONE-DIMENSIONAL BETA-DISTRIBUTION ARRAY PRODUCED IN
 THE SUBROUTINE.
 J - NUMBER OF VALUES IN BETA.
 PR - ONE-DIMENSIONAL ARRAY OF P-VALUES USED IN GENERATING
 THE BETA DISTRIBUTION

SUBROUTINE ACTAFIN(C,BETA,J,PR)
 DOUBLE PRECISION N,C,F,PP1011,G,GAMMA,BETA1011,X,DELTA,P,A,B,D,E,F
 COMMON DELTA

P = C.C
 J = 1
 BETA11 = C.C
 G = GAMMA(2.C+1.0,A-C+1.0)
 B = DLOG10(.540+01) - .770+02*

IFIC .NE. 0.01 GO TO 1
 IFIN .NE. 0.01 GO TO 3
 NN = 4
 BETA11 = G
 X = G

1 IFIN .NE. 01 GO TO 2
 NN = 1
 BETA11 = 0.0
 X = G

3 NN = 3
 BETA11 = G
 X = C.C
 GO TO 15

2 NN = 2
 BETA11 = C.C
 X = C.C
 BETA11 = C.C
 O = F + DELTA
 B11J = C

IFIC .EQ. 11. DELTA1 GO TO 45
 GO TO 110.2,30,50,50, AN
 10 B = DLOG10(P)*
 F = 1/2 *
 IFIC .GE. 51 GO TO 15 *
 BETA11J = G + C.C
 GO TO 15

20 A = DLOG10(P)*
 B = DLOG10(1.0+01 - P)*
 F = 1/2 *
 F = 1/2 *
 IFIC .GE. 51 GO TO 15

$$* \quad P^0 = (I \times 10^A)^C \geq 5.4 \times 10^{-77}$$

$$C \log(I \times 10^A) \geq \log(5.4) - 77$$

$$C \geq \frac{\log(5.4) - 77}{\log(P)}$$

CARD
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DQSF1C1C
DQSF1C2C
DQSF1C3C
DQSF1C4C
DQSF1C5C
DQSF1C6C
DQSF1C7C
DQSF1C8C
DQSF1C9C
DQSF110C
DQSF111C
DQSF112C
DQSF113C
DQSF114C
DQSF115C
DQSF116C
DQSF117C

```

      (F(NDIM-1),G,S,F
      S ALX1=Y(4)*Y(4)
      ALX1=ALX1+ALX1
      Z(5)=SUM1+Y(3)+ALX1+Y(5)
      12 Z(3)=SUM1
      Z(4)=SUM2
      RETURN
C
C      NDIM IS EQUAL TO 3
      11 SUM1=47*(1.25D0*Y(1)+Y(2)+Y(2)-25D0*Y(3))
      SUM2=Y(2)*Y(2)
      SUM2=SUM2+SUM2
      Z(1)=Y(1)+SUM2+Y(3)
      Z(1)=Z(1)
      Z(2)=SUM1
      12 RETURN
      END

```

FUNCTION GAMMA(ARG1,ARG2,ARG3)

PURPOSE
TO CALCULATE CONSTANT PART OF BETA EQUATION FOR SUBROUTINE
BETA

DESCRIPTION OF ARGUMENTS

ARG1 - CORRESPONDS TO A+2 IN BETA EQUATION
ARG2 - CORRESPONDS TO C+1 IN BETA EQUATION
ARG3 - CORRESPONDS TO N-C+1 IN BETA EQUATION

DOUBLE PRECISION FUNCTION GAMMA (ARG1,ARG2,ARG3)

DOUBLE PRECISION COEFF,X,Y,Z,ARG1,ARG2,ARG3

COEFF = 1.0

11 X = 1.0

Y = 1.0

Z = 1.0

CHECK = 0.0

IF (A1 .LE. 57.0) GO TO 12

CHECK = 1.0

ARG1 = ARG1 - 1.0

X = ARG1

12 IF (ARG2 .LE. 57.0) GO TO 13

CHECK = 1.0

ARG2 = ARG2 - 1.0

Y = ARG2

13 IF (ARG3 .LE. 57.0) GO TO 14

CHECK = 1.0

ARG3 = ARG3 - 1.0

Z = ARG3

14 COEFF = COEFF*(X/Y)*(1.0/Z)

IF (CHECK .LE. 1.0) GO TO 11

CALL GAMMA(ARG1, X, 1.0)

CALL GAMMA(ARG2, Y, 1.0)

CALL GAMMA(ARG3, Z, 1.0)

GAMMA = COEFF*(X/Y)*(1.0/Z)

RETURN

END

C

C30C
N00P00

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```

581 (F(NC,EC,AL,AD,CL,CC,CI) GC TC 2
582 (F(NC,EC,AL,AD,CL,CC,CI) GC TC 2
583 CALL GETP(NC,EC,AD,CL,CC,CI)
584 CALL GETP(NC,EC,AD,CL,CC,CI)
585 IF (L=1) J
586 IF (P17(L) .NE. P1X(L)) GC TC 1
587 AX(L) = P1X(L)
588 GO TO 100
589 ( AX(L) = P17(L)
590 ( AX(L) = P17(L)
591 CMAPA = ACAP(AX,J)
592 TMAPA = ACAP(CX,J)
593 K = CMAPA/TMAPA
594 2 QETPA
595 EN)

```

*** END OF DATA ***

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